Title: INDUSTRIAL HIGH POWER FIBER LASER SYSTEM WITH OPTICAL MONITORING ASSEMBLY

Abstract: A high power fiber laser system for processing a workpiece is configured with a plurality of laser modules each having an output feeding fiber which supports and guides laser radiation towards the workpiece, and a fiber combiner formed upon coupling the output feeding fibers together and outputting the combined laser radiation into a delivery fiber. The combiner is configured so that the combined laser radiation has a minimally possible beam quality factor (M2). The high power laser system further includes a laser head receiving the combined laser radiation and focusing the latter on the surface of the workpiece so as cause a backreflected radiation to propagate backwards through the laser head, delivery fiber and combiner towards the laser modules. The fiber laser system also is provided with a monitoring assembly receiving the backreflected radiation and operative to detect the spectrum thereof.
INDUSTRIAL HIGH POWER FIBER LASER SYSTEM WITH OPTICAL MONITORING ASSEMBLY

BACKGROUND OF THE DISCLOSURE

Field of the Disclosure

[001] The disclosure relates to high power fiber laser systems (HPFLS) for processing material in industrial methods. In particular, the disclosure relates to a HPFLS system operative to generate a high quality output beam reaching kW levels. Furthermore, the disclosure relates to HPFLSs provided with an on-line monitoring assembly of the backreflected optical emission propagating through the optical combiner.

Prior Art Discussion

[002] Laser-assisted welding, cutting, marking, drilling, cladding and other material processing industrial methods require precise control of a variety of fiber laser-assisted techniques. The high power fiber laser may output radiation in kilowatts. With such high-power outputs, the quality of the output beam presents became a focal point of research.

[003] Accordingly, the power and quality of the laser beam are among essential laser-related characteristics which may affect the material to be processed. Hence the information related, for example, to the conditions of the weld indicative of laser parameters should be closely monitored.

[004] A continuous need therefore exists for a high power fiber laser industrial system operative to deliver a powerful, high quality light.

[005] Furthermore, there is a need for a fiber combiner configured with a plurality of single mode feeding input fibers and operative to output a combined laser beam with an optimally small beam quality parameter $M^2$.

[006] Finally, there is a need to provide a high power fiber laser system with a reliable monitoring system capable of correctly detecting backreflected radiation indicative of operating conditions of the laser modules and conditions of the surface of the workpiece to be processed by a powerful, high quality laser beam.
SUMMARY OF THE DISCLOSURE

[007] The above-identified needs are met by the disclosed high power fiber laser system (HPFLS) and a method for operating the HPFLS. The disclosed system is configured with one or more fiber laser modules having respective feeding fibers, which are combined together to define a fiber combiner, and with a monitoring assembly.

[008] The combiner is configured from multiple feeding fibers and structured to guide the forward propagating radiation with the smallest possible \( M^2 \) factor - the reliable indication of the quality of light incident on the surface to be treated, as known to one of ordinary skills. In order to achieve the optima quality of light, the cumulative radiation of combined individual feeding fibers from respective laser modules should be as small as possible. The lower the \( M \) factor, the higher quality of the outcome of the material processing. The low cumulative radiation is attained by controllably modifying geometry of individual fibers and combiner so that the numerical aperture (NA) of the individual fibers and the NA the combiner output, which directly affects the \( M \) factor, are minimally possible.

[009] The combiner may be configured with one or more spare fibers that can be further connected to a monitoring assembly operative to detect backreflected radiation. Accordingly, the combiner receives the backwards propagating radiation and guides the received backreflected radiation to the monitoring assembly.

BRIEF DESCRIPTION OF THE DRAWINGS

[010] The above and other features and advantages of the disclosure are discussed herein below in conjunction with the drawings, in which:

[011] FIG. 1 is a diagrammatic view of the disclosed high fiber laser system provided with a monitoring assembly.

[012] FIG. 2 is a simplified schematic of the monitoring assembly;

[013] FIG. 3A and 3B respective side and end diagrammatic views of a fiber combiner;

[014] FIG. 4 is a diagrammatic view of laser module;

[015] FIG. 5 is a diagrammatic view of a fiber laser provided in the laser module;

[016] FIG. 6 is an diagrammatic elevated view of laser head;
FIG. 7 is a view of shield holder preventing material particles, which leave the melted surface of the workpiece, from penetrating into the laser head.

SPECIFIC DESCRIPTION

Reference will now be made in detail to the disclosed system. Wherever possible, same or similar reference numerals are used in the drawings and the description to refer to the same or like parts or steps. The drawings are in simplified form and are far from precise scale.

Referring to FIG. 1, a high power fiber laser system 10 is configured to provide for material processing including, but not limited to welding, cutting, marking, drilling, and cladding. The HPFLS 10 includes a fiber laser source 15 configured with multiple fiber laser modules 12 which have respective feeding fibers 23 operatively connected to one another in a combiner 14 which emits a high quality signal light at a predetermined wavelengths, such as 1070 nm given here only as one of numerous possible wavelengths. The signal light is coupled into a multimode delivering fiber 25 launching the light into a laser head 18. As known to one of ordinary skills in the industrial fiber laser system arts, laser head 18 is configured with focusing optics 58 directing signal light towards a workpiece 20. During the incidence of focused signal light 30 onto the surface of workpiece 20, the surface begins to melt with the generation of backreflected light emission which propagates towards the upstream of HPFL 10 through head 18 and combiner 14 towards lasers modules 12. A backreflected signal light is also propagates back to the outputs of the respective laser modules. The combined backreflected signal 34 is coupled into assembly 16 operative to monitor backreflected radiation spectrum between about 400 nm to about 2000nm, as discussed below.

When, for example, workpiece 20 is being cut or welded, emission from the molten material and reflected light at the wavelength of the signal light can be simultaneously monitored. Depending on the processing parameters of the laser modules, the melt can change. The thermal emission is sensitive to the cutting/welding front, depth of the cut and other characteristics of the cutting/welding process and, if properly monitored, may provide useful information of the quality of the work product. On the other hand, the backreflected radiation may be indicative of the absorption of the
laser power, which depends on the wavelength, and the stability of the power density. Overall, light 34, further referred as backreflected radiation, is characterized by a spectrum which is evaluated by monitoring assembly 16 and further compared to the reference in a central processing unit (CPU) 26.

[022] In accordance with one aspect of the disclosure, at least one or multiple feeding fibers 23 are in optical communication with monitoring assembly 16 via a control signal fiber 24. The backreflected radiation 34 leaving combiner 14 is uniformly distributed between feeding fibers 23 and, therefore, light coupled into monitoring unit 16 is indicative of the conditions of the process. Alternatively, instead of control signal fiber 24, combiner 14 can be configured with one or more extra fibers 28 connected directly to monitoring assembly 16. The monitoring assembly 16 may be configured with monitoring devices selected from spectrosopes, interferometers and photodiodes and operative to process the coupled backreflected radiation.

[023] FIG. 3 illustrates an exemplary configuration of monitoring assembly 16 operative to detect visible, NIR and/or UV wavelength ranges of backreflected radiation (Li) 34 and output signal or signals Io which further match to a reference value - respective empirically determined desired ranges in CPU 26. If no match is determined, CPU 28 generates a control signal Ic coupled into the laser modules so as to modulate parameters of the lasers improving the work product, i.e., a cut, weld or any other operational results.

[024] The control signal fiber 24, for example, is coupled into an SMA 21 mounted to the housing of assembly 16 and optically connected to a fiber collimator (not shown) operative to focus backreflected radiation (Li) 34 inside the housing. The focused radiation is incident upon the input port of a light-guiding component configured to direct the focused radiation along one or more measuring paths towards optoelectronic components.

[025] The light-guiding component may be selected from beam splitters (not shown), circulators and the like. As shown in FIG. 3, the light-guiding component is configured as a circulator 36 having an input and one or more output ports optically coupled to respective photodiodes. Given only as an example, three output ports of circulator 36 are
associated with respective optical filters, which are not shown but well known to a
POSITA, which in turn are optically connected to respective photodiodes 32, 34 and 38.

[026] One of the photodiodes, for example 32, is operative to detect the process emission in the wavelength range between about 400 nm and about 1000 nm (in the following Visible signal). This photodiodes ensure the evaluation of the process emission related to both continuous thermal emission and backreflected radiations. Visible domain can be divided into two main ranges, (400 nm- 550 nm) and (550nm - 800nm), to better represent continuous emission shifts. Thus, in this configuration very low levels of incoming light can be catch by each of the photodiode in the visible range, requiring complex solutions for signal conditioning.

[027] The other two photodiodes are used to collect NIR radiation. The first one 34 is filtered with a laser line filter and is operative to evaluate backreflected or backscattering signal light. This photodiode is aimed at monitoring completely penetrated welds, where the aperture of the key hole on the root side of the welds shows a high attenuation of the laser beam backscattering.

[028] The other photodiode 38 collects emission between 1150 nm and 1800 nm passed through a respective filter. The acquired signal is related to the near infra-red thermal emission of the process. Generally the time behavior of this photodiode is comparable to the one of the visible signals and their comparison can also warrant control of focus position by chromatic aberration analysis.

[029] The signals from the photodiodes are acquired, conditioned and sampled by CPU 26. If the obtained spectrum in any of the detected ranges does not substantially match the stored reference values, a control sign Ic is output to the laser modules whose parameters, such as output power, are continuously adjusted to obtain the desired spectra of the backreflected radiation.

[030] Referring to FIGS. 1 and 3A-3B, one of many salient features of the disclosed material processing system includes a high quality beam incident on the surface of workpiece 20. The beam quality may be characterized by an M² factor, as well known to a person of ordinary skills in the art (POSITA). The lower the M² factor, the higher the beam quality. In some applications, the beam quality factor is not critical, in others, as rather typical a case, it is.
In case of the high beam quality beam parameter, combiner 14 should output an optimally small far-field divergence signal light 30 characterized by the smallest possible $M^2$ factor. In other words, any further reduction of this factor would be associated with deteriorating beam quality. The $M^2$ factor of the combiner's output is determined in as

$$M^2 = \frac{N_A\text{measured}}{N_A\text{ideal}}$$

where $N_A$ is a numerical aperture of the combiner.

The feeding single mode fibers 23 are initially arranged in accordance with FIG. 3A and then are heated and stretched. During the stretching, the claddings of respective fibers 23 gradually merge with one another to eventually define the outer boundary of the combiner's output, i.e., multimode delivering fiber 25 of FIG. 3B. Preferably, outputs of respective fiber laser modules supported by respective feeding fibers 23 each are substantially in a fundamental mode. While the numerical aperture and diameter of each fiber 23 reduce, its mode, which has substantially a Gaussian profile ($M^2$ is about 1) enlarges. If the attenuation of each feeding fiber 23 is not controlled, than the modes may reach the fiber cladding. This, in turn, leads to deterioration of combiner's output. Accordingly, the output of disclosed combiner 14 owns its high quality to the preservation of substantially Gaussian shape supported by each individual SM fiber 23. The latter, in turn, has a controlled minimal possible numerical aperture (NA) below which the single mode in this fiber touches the cladding.

In order to avoid the coupling of any single mode into the cladding of combiner 14 shown in dash lines in FIG. 3B, the numerical apertures (NA) of each feeding fiber 23 and combiner 14 are continuously measured and compared to the stored reference value. Once the ratio between the measured NA of combiner 14 (as a function of the effective area, i.e., area limited by a circumference around tops of respective modes), is determined and compared to a stored reference value in CPU 26. Accordingly, multimode delivering fiber 25 controllably supports a high quality signal light 30.

FIG. 4 illustrates laser module 12. In accordance with a further salient feature of the disclosure, the module has a housing enclosing one or more gain blocks 50. For example, block 50 may be configured with a single-stage laser or oscillator generating a 500 or more watt output. In a further modification, each module 12 may be configured
with multiple fiber gain blocks 50 including serially coupled oscillators and fiber amplifiers. The fiber block receives pump light generated by a pump assembly which may be configured with another single mode fiber laser or lasers 51 which in turn are pumped by multiple broad-area laser diodes (not shown). The pumping arrangement may be configured as a side- or end-pumping arrangement.

[035] FIG. 5 illustrates the configuration of fiber gain block 50 which preferably generates radiation in a substantially single fundamental mode which, as known to a POSITA, contains maximum light power. The gain block 50 includes an active fiber 52 having a multimode (MM) core which is doped with ions of rare-earth elements. The MM core is configured to support substantially a fundamental mode at the desired wavelength. The opposite ends of active fiber 52 are butt-spliced to respective ends of SM passive input and output fibers 54, 56. To prevent the excitation of higher modes and therefore loss of light at splice regions, the active and passive fibers are configured with substantially identical mode field diameters. The output passive fibers 54 are fused to respective feeding fibers 23, which, in turn, are coupled together to define fiber combiner 14.

[036] Referring to FIGS. 1, 6 and 7, the backreflected radiation 34 also creates unfavorable conditions for focusing optics 58 of laser head 18. In particular, the thermal diffusion is accompanied by material particles leaving the surface of workpiece 20 and impinging upon the opposing component of optics, such as a protective transparent shield 68. The damage to shield 68 inflicted by impinging particles causes the loss of light propagating through protective glass, inferior material processing results and damage to focusing optics 58 of head 18.

[037] When shield 68 is not compromised, there is practically no light scattered through the shield. However, if shield 68 is damaged, scattering light may be detected and evaluated in CPU 26 (FIG. 1). If the power threshold for the scattered light exceeds the empirically selected threshold, fiber laser system 10 should be shut down.

[038] In accordance with a further aspect of the disclosure, the scattering light is detected by a fiber 66 removably around the perimeter of a shield holder 62. If the shield 68 is damaged, scattering light tends to propagate in all directions. Necessarily propagating through fiber 66, the scattering light is further guided by this fiber to an
optoelectronic component 70 which is operatively connected to CPU 26 or any other controller. If shield 68 is determined to be unacceptable for further use, holder 62, which is pivotally mounted to the housing of laser head 18, can be easily opened to grant access to the shield.

[039] Although there has been illustrated and described in specific detail and structure of operations, it is understood that the same were for purposes of illustration and that changes and modifications may be made readily therein by those skilled in the art without departing of the scope of this disclosure.
CLAiMS:

1. A high power fiber laser system for processing a workpiece, comprising:
   a plurality of laser modules each having an output feeding fiber which supports and
guides laser radiation towards the workpiece;
   a fiber combiner having the output feeding fibers of the respective modules coupled
together into a multimode delivery fiber which guides combined laser radiation from the
laser modules along a light path, the optical combiner being configured so that the
combined laser radiation has a minimally possible beam quality factor (M^2);
   a laser head receiving the combined laser radiation and operative to direct the
combined laser radiation towards a surface of the workpiece so as cause a backreflected
radiation to propagate backwards along the light path through the laser head, delivery
fiber and combiner towards the laser modules; and
   a monitoring assembly receiving the backreflected radiation and operative to detect a
spectrum of the backreflected radiation.

2. The high power fiber laser system of claim 1 further comprising a control signal fiber
receiving the backreflected radiation from one or more of the feeding fibers and
delivering the backreflected radiation to the monitoring assembly.

3. The high power fiber laser system of claim 1, wherein the fiber combiner is configured
with an additional control signal fiber delivering the backreflected radiation to the
monitoring assembly.

4. The high power fiber laser system of claim 1 further comprising a controller receiving
the detected spectrum from the monitoring assembly and operative to match the detected
spectrum to a reference value, the backreflected radiation including thermal emission and
backreflected laser signals in UV, NIR and visible ranges from about 400 nm to about
2000 nm.

5. The high power fiber laser system of claim 1, wherein the feeding fibers are configured
as respective single mode fibers each with a minimally possible small numerical aperture
which, upon coupling the feeding fibers together, provide for the minimally possible beam quality factor (M\textsuperscript{2}) of the combined laser radiation.

6. The high power fiber laser system of claim 1, wherein the monitoring assembly is configured with

   - an optical guide component selected from the group consisting of beam splitters, isolators and circulators which are operative to route the backreflected along multiple light paths within the monitoring assembly, and
   - sensors selected from the group consisting of spectroscopes, interferometers and photodiodes optically coupled to the respective optical guide components.

7. The high power fiber laser system of claim 1, wherein the laser modules each are configured with an active fiber and input and output passive fibers butt-spliced to respective opposite ends of the active fiber, the active fiber having a multimode core doped with a gain medium and configured to support propagation of a single mode at a desired wavelength, the passive fibers each being single mode fibers and having a mode field diameter (MFD) substantially equal to an MFD of the active fiber.

8. The high power fiber laser system of claim 7, wherein the laser modules each further have a pumping unit provided with one or multiple single mode fiber lasers.

9. The high power fiber laser system of claim 1, wherein the laser head has a protective shield opposing the workpiece, and a sensing fiber surrounding the protective shield and operative to detect scattering light indicative of a damage of the protective shield.

10. A high power fiber laser system for processing a workpiece, comprising:

    - a plurality of laser modules each having an output feeding fiber which supports and guides laser radiation towards the workpiece, the output feeding fibers being coupled together so as to define a fiber combiner with a delivery fiber which guides a combined laser radiation from the plurality of the laser modules along a light path, the fiber
combiner being configured so that the combined laser radiation has a minimally possible beam quality factor (M²) upon impinging upon a surface of the workpiece; and

a monitoring assembly receiving a backreflected radiation, which is generated in response to the combined laser radiation incident upon the surface, from the combiner and operative to detect a spectrum of the received backreflected radiation.

11. The high power fiber laser system of claim 10, wherein the combiner is configured with an additional control signal fiber launching the backreflected radiation into the monitoring assembly.

12. The high power fiber laser system of claim 10 further comprising a controller receiving the detected spectrum from the monitoring assembly and operative to match the detected spectrum to a reference value, the backreflected radiation including thermal emission and backreflected laser signals in UV, NIR and visible ranges from about 400 nm to about 2000 nm.

13. The high power fiber laser system of claim 10, wherein the feeding fibers are configured as respective single mode fibers each with an optimally small numerical apertures (NA) which, upon coupling the feeding fibers together, provide for the minimally possible beam quality factor (M²), each optimally small NAs being the smallest one which, upon coupling the feeding fibers together, provide for the minimally possible beam quality factor M² of the combined laser radiation.

14. The high power fiber laser system of claim 12, wherein the monitoring assembly is configured with a plurality of sensing channels configured to sense respective UV, NIR and visible ranges.

15. The high power fiber laser system of claim 10, wherein the laser modules each are configured with an active fiber and input and output passive fibers butt-spliced to respective opposite ends of the active fiber, the active fiber having a multimode core doped with a gain medium and configured to support propagation of a single mode at a
desired wavelength, the passive fibers each being single mode fibers and having a mode field diameter (MFD) substantially equal to an MFD of the active fiber.

16. The high power fiber laser system of claim 10 further comprising a laser head located between the fiber combiner and the workpiece and configured to focus the combiner laser radiation onto the workpiece, the laser head having a protective shield facing the workpiece and a sensing fiber surrounding the protective shield and operative to detect scattering light indicative of a damage of the protective shield.

17. A method of operating the high power fiber laser system of claim 1, comprising:
coupling a plurality of single mode output laser beams into respective feeding fibers;
stretching the feeding fibers while monitoring numerical apertures (NAs) of each individual feeding fiber so as to prevent coupling of a Gaussian-profile mode into a cladding of the feeding fiber;
simultaneously with stretching coupling the feeding fibers together so as to provide for a fiber combiner with an output multimode delivery fiber which guides a combined multimode output laser radiation, having a lowest possible beam quality factor (M²), towards a workpiece to be laser treated;
coupling backreflected radiation generated in response to the combined laser radiation incident on a surface of the workpiece into the delivery fiber, which guides the coupled backreflected radiation to the combiner; and
monitoring the backreflected radiation received from the combiner so as to detect a spectrum of the backreflected radiation.

18. The method of claim 17, wherein the combiner has an additional control signal fiber launching the backreflected radiation onto the monitoring assembly.

19. The method of claim 17 further comprising monitoring scattered light indicative of a damaged protective shield which is configured to prevent penetrations of particles of the workpiece accompanying the backreflected radiation into a laser head located between the delivery fiber and the workpiece.
20. The method of claim 19 further comprising providing a fiber around the shield so as to receive the scattered light, and matching the received scattered with a reference value.
### B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

B23K 26/36; HOIS 3/067; HOIL 21/324; B23K 26/06; B23K 26/00

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Korean utility models and applications for utility models

Japanese utility models and applications for utility models

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

eKOMPASS(KIPO internal) & Keywords: fiber, laser, combiner, monitor, backreflect

### C. DOCUMENTS CONSIDERED TO BE RELEVANT

<table>
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<th>Category</th>
<th>Citation of document, with indication, where appropriate, of the relevant passages</th>
<th>Relevant to claim No.</th>
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<td>A</td>
<td>KR 10-2009-0112282 A (LTS CO., LTD.) 28 October 2009 See Abstract; Figures 2, 3 and Claim 1</td>
<td>1-20</td>
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<td>A</td>
<td>JP 2007-044739 A (MIYACHI TECHNOIS CORP.) 22 February 2007 See Abstract and Figure 1</td>
<td>1-20</td>
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Further documents are listed in the continuation of Box C.

See patent family annex.

* Special categories of cited documents:
  "A" document defining the general state of the art which is not considered to be of particular relevance
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Date of the actual completion of the international search

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Name and mailing address of the ISA/KR

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